

FDS6898A

Dual N-Channel Logic Level PWM Optimized PowerTrench[®] MOSFET

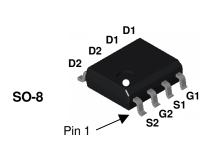
General Description

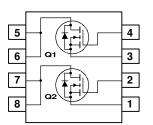
These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

- 9.4 A, 20 V $\begin{array}{c} R_{\text{DS}(\text{ON})} = 14 \ m\Omega \ @ \ \text{V}_{\text{GS}} = 4.5 \ \text{V} \\ R_{\text{DS}(\text{ON})} = 18 \ m\Omega \ @ \ \text{V}_{\text{GS}} = 2.5 \ \text{V} \end{array}$
- Low gate charge (16 nC typical)
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability





Absolute Maximum Ratings T_{A=25°C} unless otherwise noted

| Symbol | Parameter | | | Ratings | U | nits | | |
|-----------------------------------|--|---|----------|-----------|-------------|---------|------|--|
| V _{DSS} | Drain-Sour | Drain-Source Voltage | | | 20 | | V | |
| V _{GSS} | Gate-Source Voltage | | | ± 12 | | V | | |
| ID | Drain Curre | ent – Continuous | | (Note 1a) | 9.4 | | А | |
| | | – Pulsed | | | 38 | | | |
| P _D | Power Dissipation for Dual Operation | | | | 2 | , | W | |
| | Power Dissipation for Single Operation (Note 1a) | | | (Note 1a) | 1.6 | | 1 | |
| | | | | (Note 1b) | 1 | | | |
| | | | | (Note 1c) | 0.9 | | | |
| T _J , T _{STG} | Operating a | and Storage Junction T | emperatu | re Range | -55 to +150 | c | °C | |
| Therma | l Charac | teristics | | | | | | |
| $R_{\theta JA}$ | Thermal Re | Thermal Resistance, Junction-to-Ambient | | (Note 1a) | 78 | °C | C/W | |
| $R_{\theta JC}$ | Thermal Re | esistance, Junction-to-C | Case | (Note 1) | 40 | °C | C/W | |
| Packag | e Markin | g and Orderin | g Infor | mation | | | | |
| Device Marking | | Device | Ree | el Size | Tape width | Quanti | ity | |
| FDS6898A | | FDS6898A | - | 13" | 12mm | 2500 ur | nits | |

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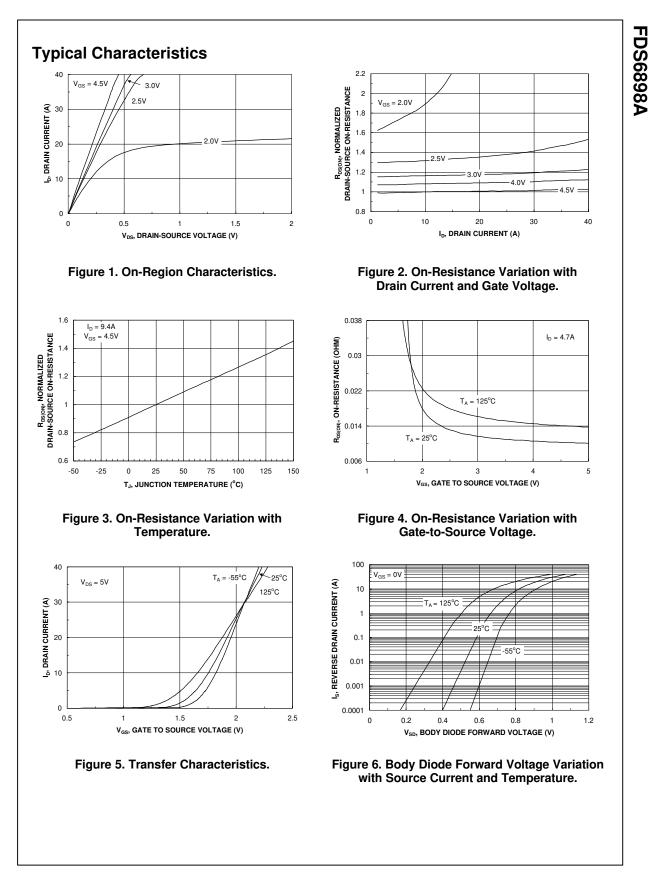
FDS6898A

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|--|---|---|-----|----------------|----------------|-------|
| Off Char | acteristics | | 1 | 1 | 1 | I |
| BV _{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0 V$, $I_D = 250 \mu A$ | 20 | | | V |
| <u>ΔBVdss</u> ΔTj | Breakdown Voltage Temperature Coefficient | $I_D = 250 \ \mu\text{A}$, Referenced to 25°C | | 21 | | mV/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | $V_{\text{DS}} = 16 \text{ V}, \qquad V_{\text{GS}} = 0 \text{ V}$ | | | 1 | μA |
| I _{GSSF} | Gate-Body Leakage, Forward | $V_{\text{GS}} = 12 \ V, V_{\text{DS}} = 0 \ V$ | | | 100 | nA |
| GSSR | Gate-Body Leakage, Reverse | $V_{GS} = -12 \ V, V_{DS} = 0 \ V$ | | | -100 | nA |
| On Char | acteristics (Note 2) | | | | | |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, \qquad I_D = 250 \ \mu A$ | 0.5 | 1 | 1.5 | V |
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate Threshold Voltage Temperature Coefficient | I_D = 250 µA, Referenced to 25°C | | -3.5 | | mV/°C |
| R _{DS(on)} | Static Drain–Source On–Resistance | $ \begin{array}{l} V_{GS} = 4.5 \ V, \ I_D = 9.4 \ A \\ V_{GS} = 2.5 \ V, \ I_D = 8.3 \ A \\ V_{GS} = 4.5 \ V, \ I_D = 9.4 \ A, T_J = 125^\circ C \end{array} $ | | 10 13 14 | 14 18 21 | mΩ |
| I _{D(on)} | On-State Drain Current | $V_{GS} = 4.5V, \qquad V_{DS} = 5 \ V$ | 19 | | | Α |
| g _{FS} | Forward Transconductance | $V_{\text{DS}} = 5 \text{ V}, \qquad I_{\text{D}} = 9.4 \text{ A}$ | | 47 | | S |
| Dynamio | c Characteristics | | | | | |
| Ciss | Input Capacitance | $V_{DS} = 10 V$, $V_{GS} = 0 V$, | | 1821 | | pF |
| Coss | Output Capacitance | f = 1.0 MHz | | 440 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 208 | | pF |
| Switchir | ng Characteristics (Note 2) | | | | | |
| t _{d(on)} | Turn-On Delay Time | $V_{\text{DD}} = 10 \text{ V}, \qquad I_{\text{D}} = 1 \text{ A},$ | | 10 | 20 | ns |
| tr | Turn–On Rise Time | $V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$ | | 15 | 27 | ns |
| t _{d(off)} | Turn-Off Delay Time | | | 34 | 55 | ns |
| t _f | Turn–Off Fall Time | | | 16 | 29 | ns |
| Qg | Total Gate Charge | $V_{DS} = 10 V$, $I_{D} = 9.4 A$, | | 16 | 23 | nC |
| Q _{gs} | Gate-Source Charge | $V_{GS} = 4.5 V$ | | 3 | | nC |
| Q _{gd} | Gate-Drain Charge | | | 4 | | nC |
| Drain-S | ource Diode Characteristics a | and Maximum Ratings | | | | |
| ls | Maximum Continuous Drain-Source | Diode Forward Current | | | 1.3 | Α |
| | Drain–Source Diode Forward | $V_{GS} = 0 V, I_{S} = 1.3 A$ (Note 2) | | 0.7 | 1.2 | V |

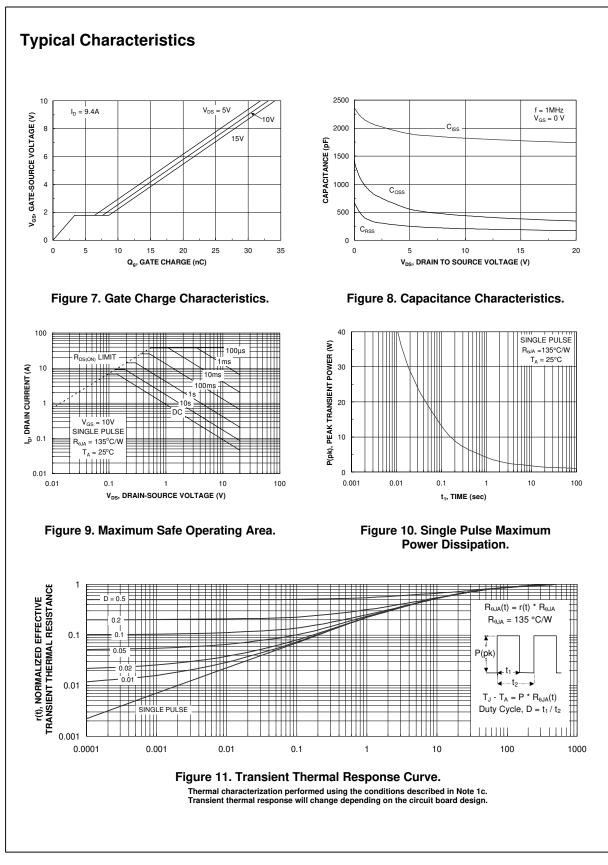
Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied



FDS6898A Rev C (W)



FDS6898A Rev C (W)

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| Product Status | Definition | | | |
|---------------------------|---|--|--|--|
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Rev. H4